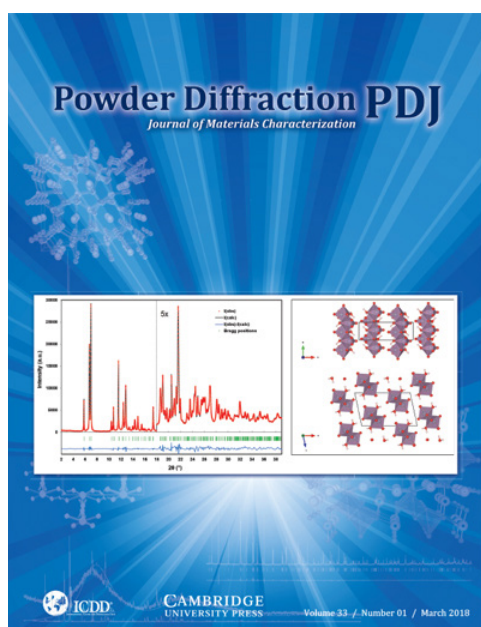


Powder Diffraction

An International Journal of Materials Characterization

Published quarterly by Cambridge University Press
(with topical supplements)

Powder Diffraction focuses on materials characterization employing X-ray powder diffraction and related techniques. With feature articles covering a wide range of applications, from mineral analysis to epitaxial growth of thin films to advances in application software and hardware, this journal offers a wide range of practical applications.



- Techniques and procedures in X-ray powder diffractometry
- Advances in instrumentation
- Study of materials including organic materials, minerals, metals and thin film superconductors
- Publication of powder data on new materials

Electronic Access:

journals.cambridge.org/core/journals/powder-diffraction

Subscription Information:

subscriptions_newyork@cambridge.org

Subscription Rates (USD\$)

Institutional	2018	2019
Print/Online	\$472	\$496
Online	\$285	\$299
Individual		
Print/Online	\$236	\$247
Online	\$166	\$174
Student	\$ 35	\$ 35

To subscribe please contact:
Cambridge University Press

1 Liberty Plaza, Floor 20
New York, NY 10006

phone: 212.337.5000

toll free: 800.872.7423

fax: 212.691.3239

email: subscriptions_newyork@cambridge.org



www.icdd.com | marketing@icdd.com

ICDD, the ICDD logo and PDF are registered in the U.S. Patent and Trademark Office. Powder Diffraction File is a trademark of JCPDS—International Centre for Diffraction Data. ©2017 JCPDS—International Centre for Diffraction Data.